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Figure 1. Grain sorghum (left) and Sweet sorghum (right)

Introduction

- Crop models can help us better understand the effects of different crop traits and environmental conditions on crop growth and yield.
- Efforts to model sweet sorghum growth and yield have been limited despite recent global interest in sweet sorghum as a bioenergy crop (Fig. 1).
- Our objective was thus to calibrate and validate the DSSAT grain sorghum model to simulate sweet sorghum growth, partitioning, and dry matter yield.

Materials and Methods

♦ Cultivar: 'M81E' sweet sorghum

♦ Data sets:

Growth sampling over 2012-13 in Citra, FL. Planting Date Study in two locations in FL¹. Nitrogen fertilization study two locations in FL²

- ◆ Parameter values for DSSAT Sweet Sorghum for SLW, G2 and PHINT are based on the growth sampling measurements collected in Citra Florida. We measured leaf weight, leaf area, leaf number, and panicle weight over time.
- Parameter values for RUE and RTPC are from sweet ghum experiments from literature^{3/4}.
- The partitioning parameter for stem and panicle growth during grain filling was derived from experiments.

UF FLORIDA Parameterization of the DSSAT Sorghum Model to Simulate Sweet Sorghum Growth and Dry Matter Partitioning

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Calibration

grain filling in grams per plant.

Parameter	Grain Sorghum	
RUE ^{a3}	3.4	
SLW ^b	0.0053, 0.0078	
RTPC ^{c4}	0.25	
G2 ^d	5 to 6	
PHINT ^e	49	
K (GS4) ^f	0.07	

and 30% to the panicle.



Validation

SO	r-

Plant Part	RMSE
Shoot Dry Weight	3733
Stem Dry Weight	3705
Head Dry Weight	1585
Leaf Dry Weight	1387

